

Power and EM Attacks on Passive 13.56 MHz RFID Devices

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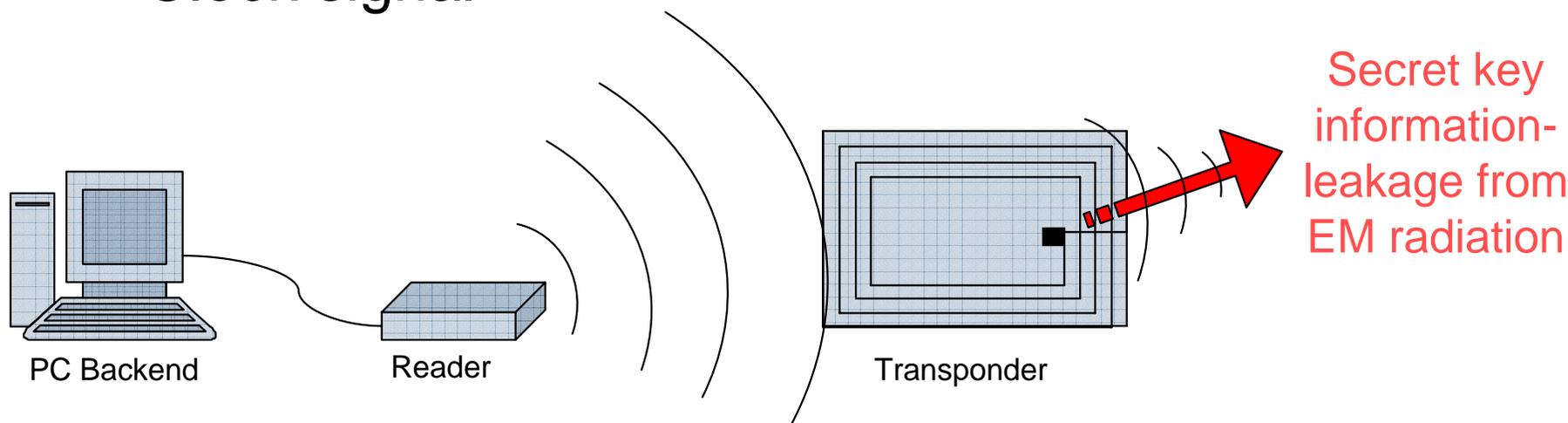
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Presentation Outline

- Introduction
- RFID prototype devices
- Measurement setups
- Results
- Conclusions and future work

Introduction

- RFID (Radio Frequency Identification)
- Air interface
 - Power supply
 - Communication
 - Clock signal



Side-Channel Attacks on RFID

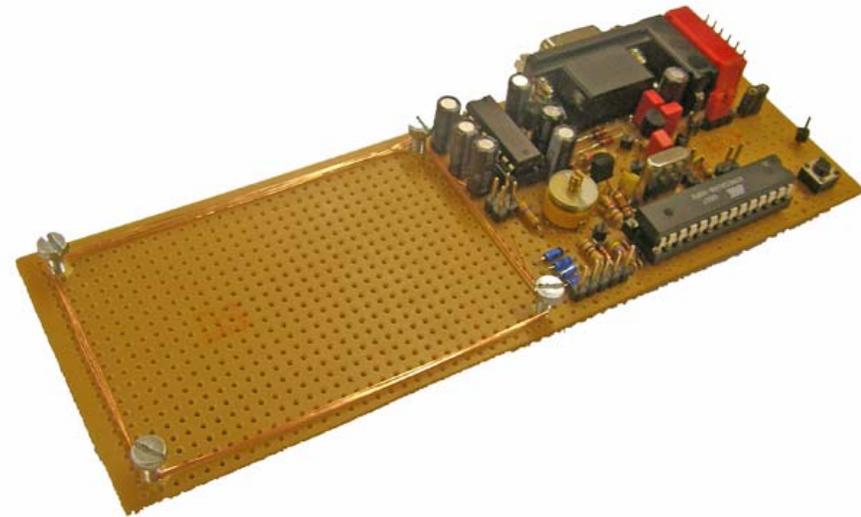
- Conventional DPA
 - Problem: No power supply contacts available
- EM analysis
 - Problem: Strong RF field of the reader superposes all interesting chip emissions
- Challenge:
 - Circumvent the interfering reader signal through filtering or signal-cancellation techniques

Side-Channel Analysis

- Side-channel analysis of two different RFID prototype devices
 - Prototype with a microcontroller (software AES)
 - Prototype with an AES coprocessor (hardware AES)

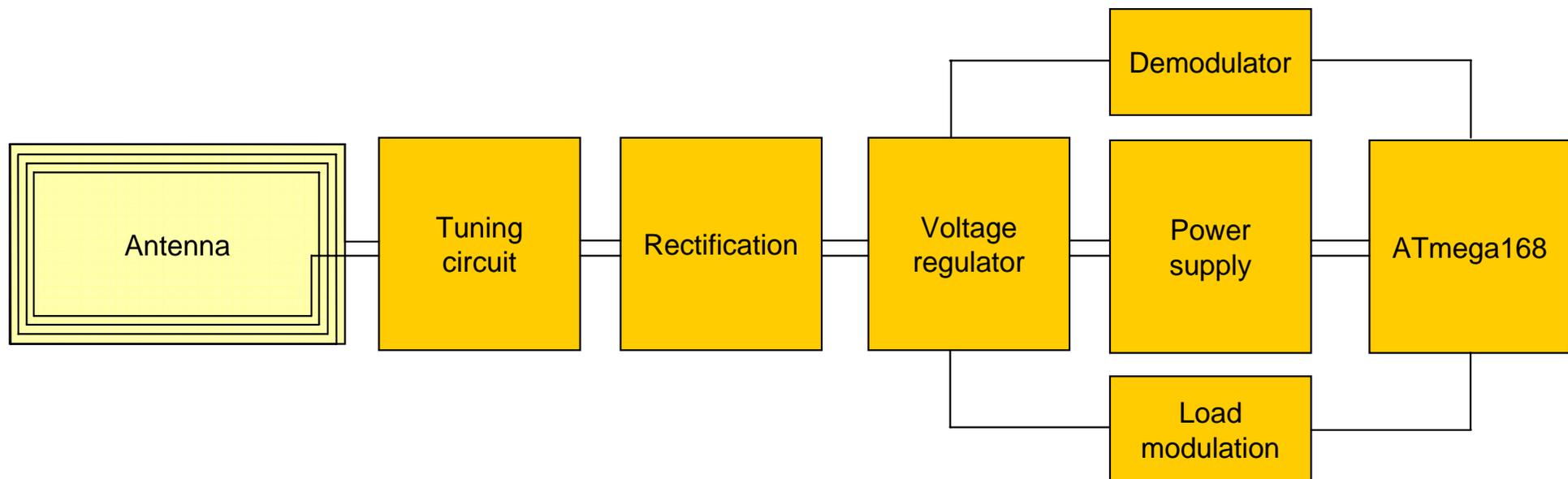
RFID Prototype with a Microcontroller

- Passive RFID tag
- Low-power design
- ISO-15693
- Software AES is used in a challenge-response protocol



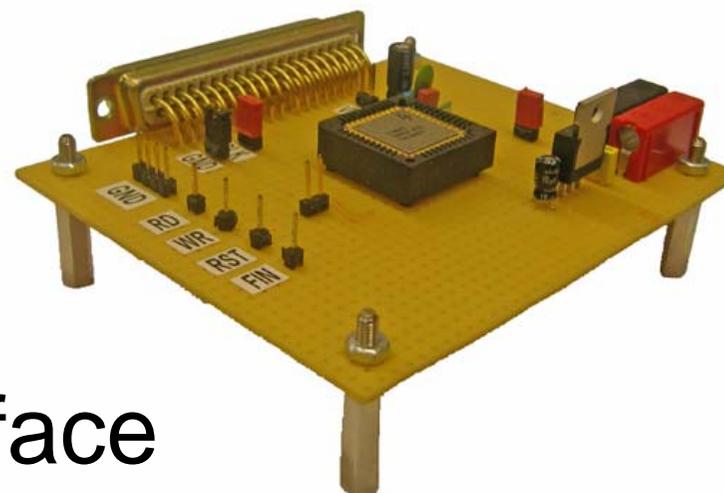
Block Diagram

- Antenna
 - ISO-7810, four windings
- Analog front-end



RFID Prototype with AES Coprocessor

- Small AES hardware implementation
 - 0.25 mm² chip die-size
 - 0.35 μ m CMOS process
- Low power
 - ~3 μ A of current @ 100 kHz
- 8-bit microcontroller interface
- Controlled via an FPGA board
- Passively powered using an additional RFID antenna



RFID Prototype vs. Single-Chip Tag

- Larger parasitic antennas
- Analog front-end and digital chip on the same die
- Low-power consumption
- Clock synchronization
- Trigger signal

Measurement Setups Overview

- Resistor
- EM probes
- EM probes and a receiver
- Helmholtz arrangement

Power Measurement Setups (1)

■ Resistor

- Traditional power measurement
- Placed between the analog front-end and the digital circuit
- Used as a reference attack

■ EM probes

- Bandwidth: 0 – 50 MHz and 30 – 3000 MHz
- Positioning: directly upon the chip (parallel to the chip layer)



Power Measurement Setups (2)

- EM probe and a receiver

- Spectrum analyzer (*ESPI R&S*)
- Connected to the oscilloscope
- Used to filter and amplify emitted frequency bands



Picture R&S®

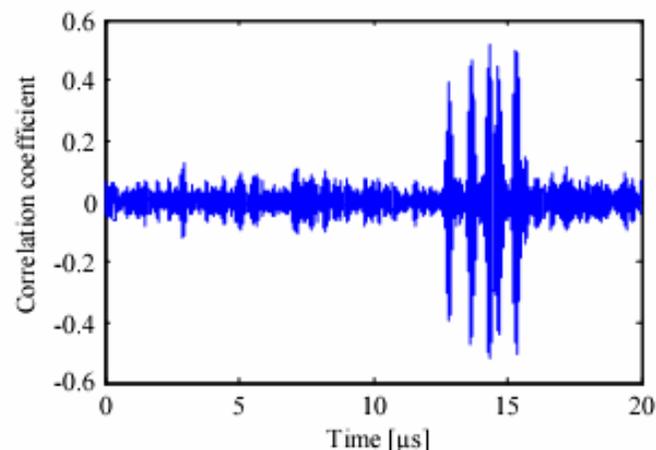
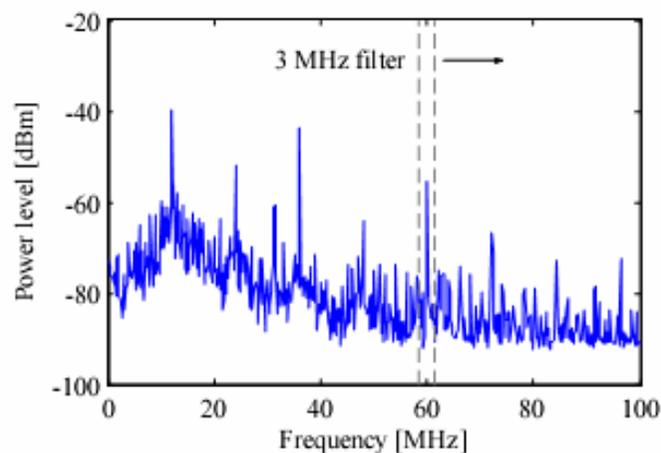
- Helmholtz arrangement

- Specified in the ISO-10373-6 standard
- Normally used for compliance testing
- Reader coil and two sense coils
- Carrier attenuation of 40dB



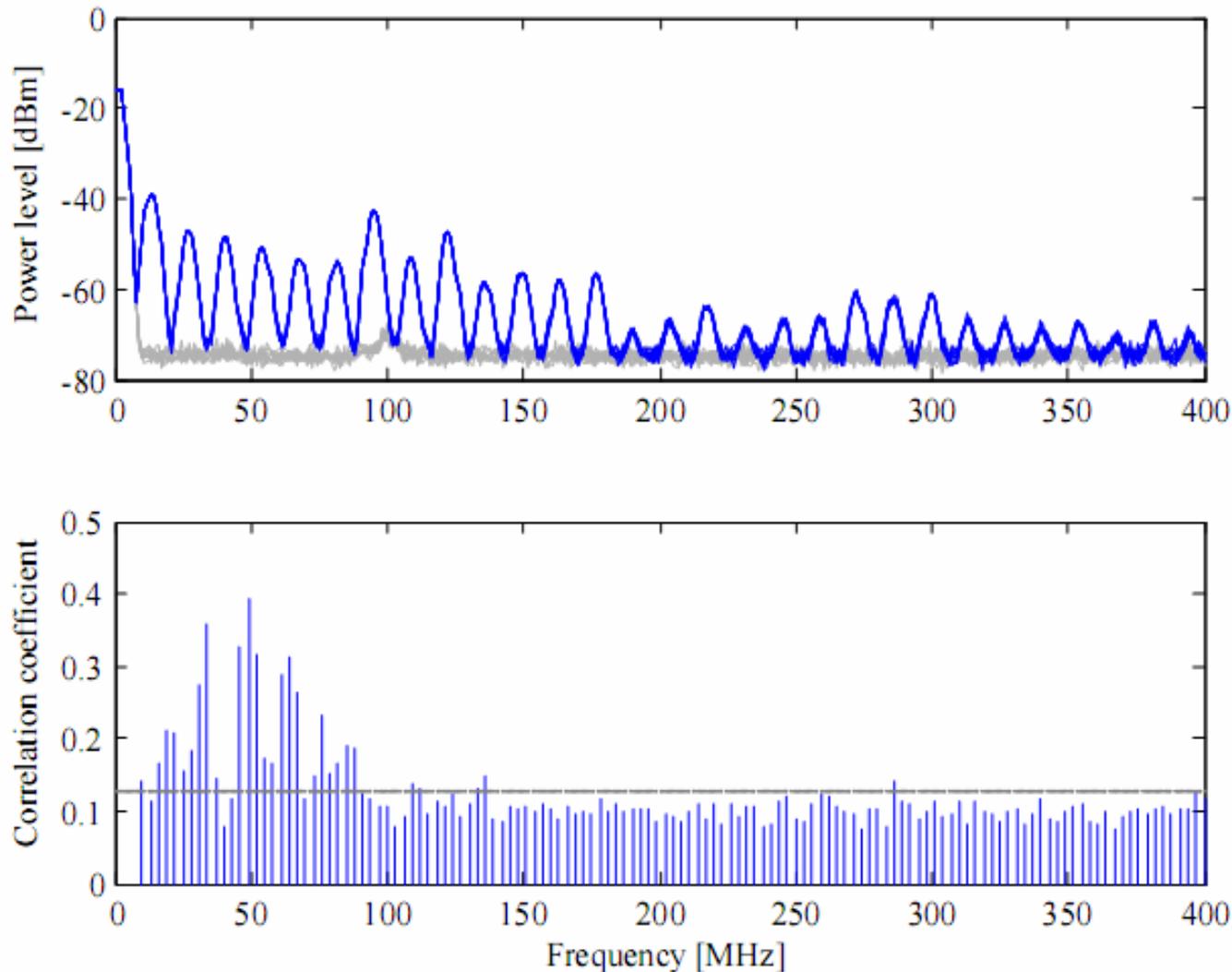
Filtering Data-Dependent Emissions

- Find the highest data-dependent frequency in the EM spectrum
- Apply the filter inside the reader field

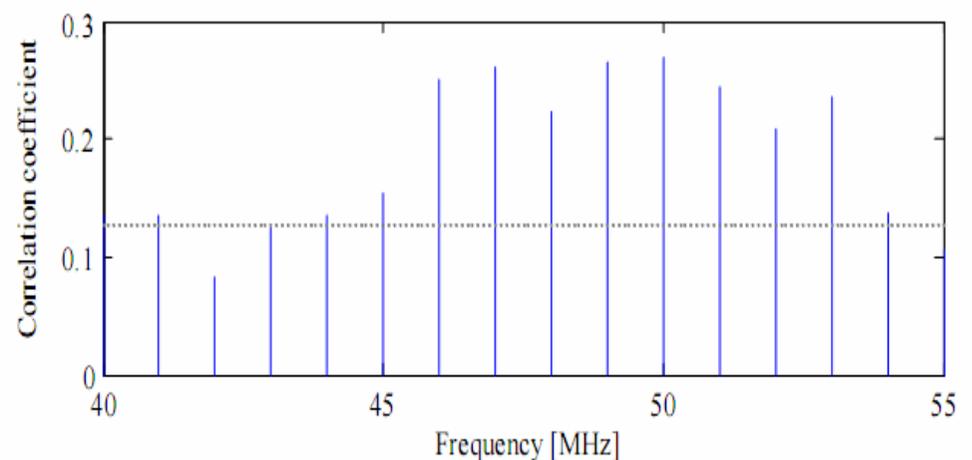
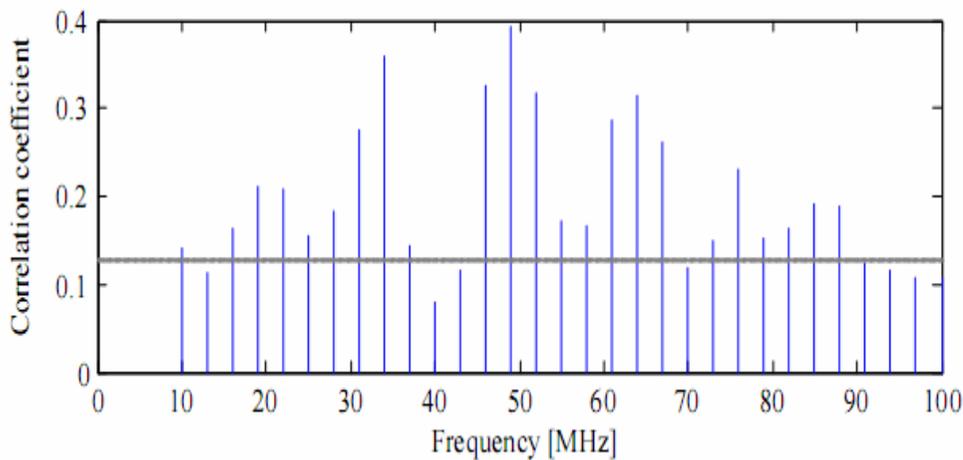
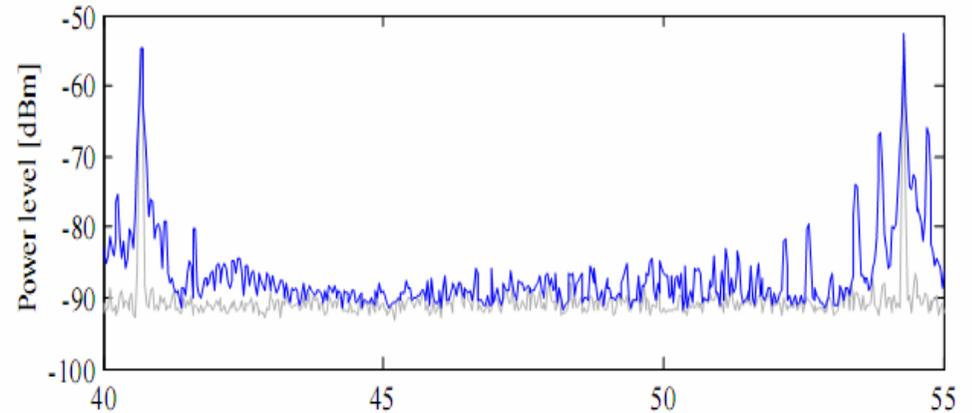
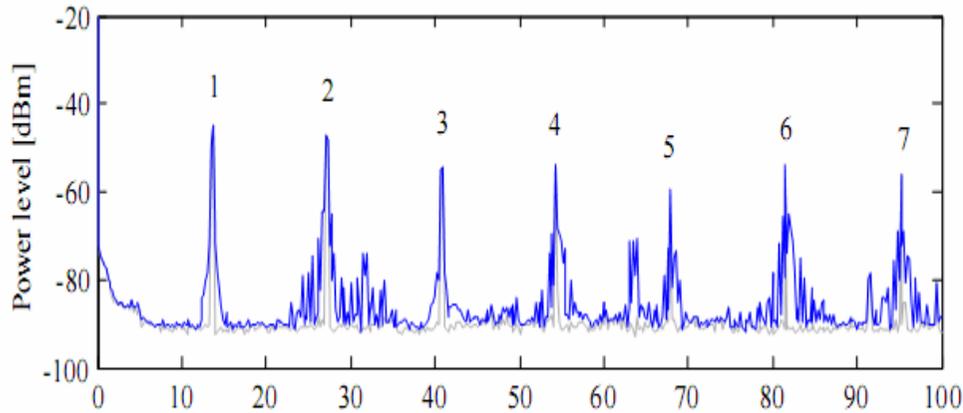


- Filter bandwidths of 10 MHz, 3 MHz, 1 MHz and 1 kHz used
- 1000 traces have been captured on each frequency band

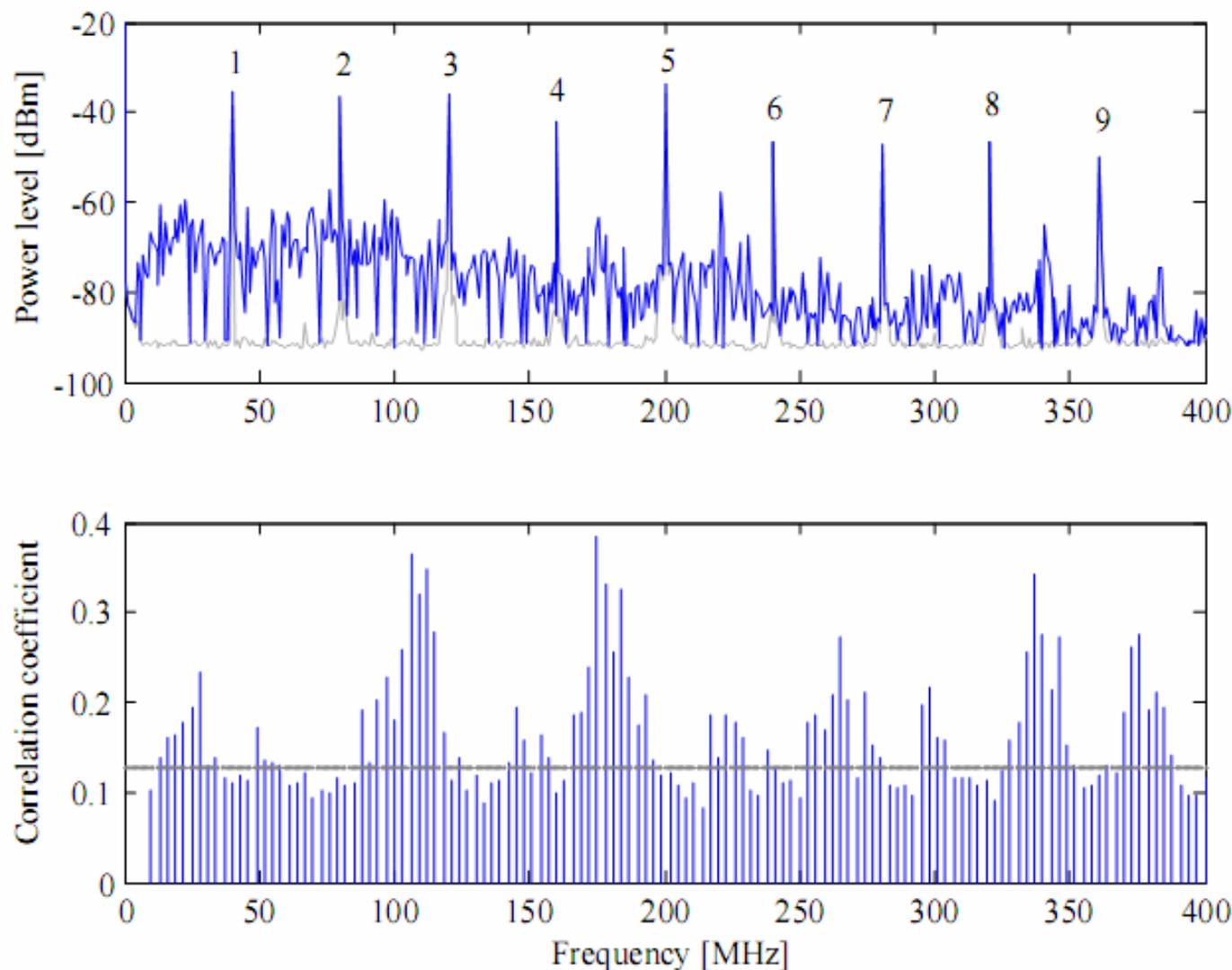
Side-Channel Leakage across the EM Spectrum of the RFID Prototype with a Microcontroller



Zoom into the Spectrum



Side-Channel Leakage across the EM Spectrum of the RFID Prototype with an AES Coprocessor



Performed Attacks

- Power and EM
- Helmholtz arrangement
- Attacking Scenarios
 - Actively and passively powered
 - Placed inside and outside the RF field of the reader
- 10,000 traces have been recorded
- Hamming-weight model
- Target: first S-box output in round one of AES

Results

	DPA		DEMA		Helmholtz
	Actively powered	Passively powered	Actively powered	Passively powered	Passively powered
	Outside	Inside	Outside	Inside	Inside
Micro-controller	0.64 (~50)	0.67 (~45)	0.73 (~35)	0.19 (~770)	0.06 (~7700)
AES coprocessor	0.39 (~170)	0.17 (~970)	0.34 (~225)	0.15 (~1200)	N/A

Conclusions and Future Work

- Contact-less devices are as vulnerable as contact-based devices

- Attacks can be further improved
 - Increasing the SNR of the measurement setup
 - Advanced filtering
 - Improved reader-field cancellation techniques

- Characterization of data-dependent frequency emissions

Side-Channel Analysis Lab



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